

*Effect of bias voltage on full  
depletion voltage measured for  
different materials*

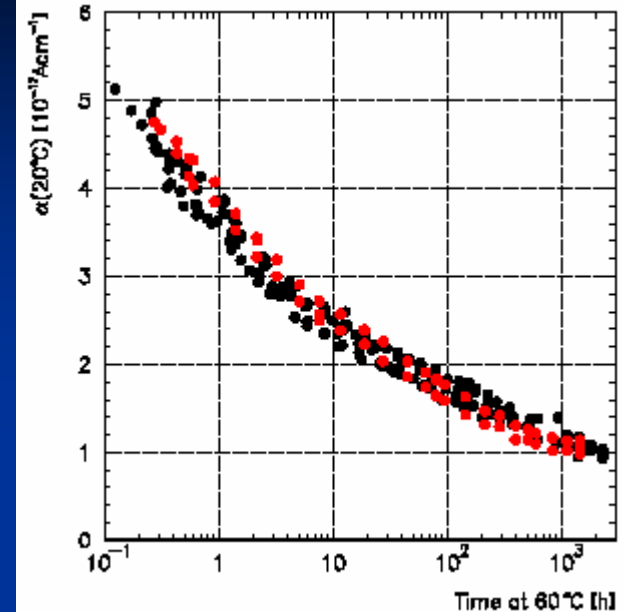
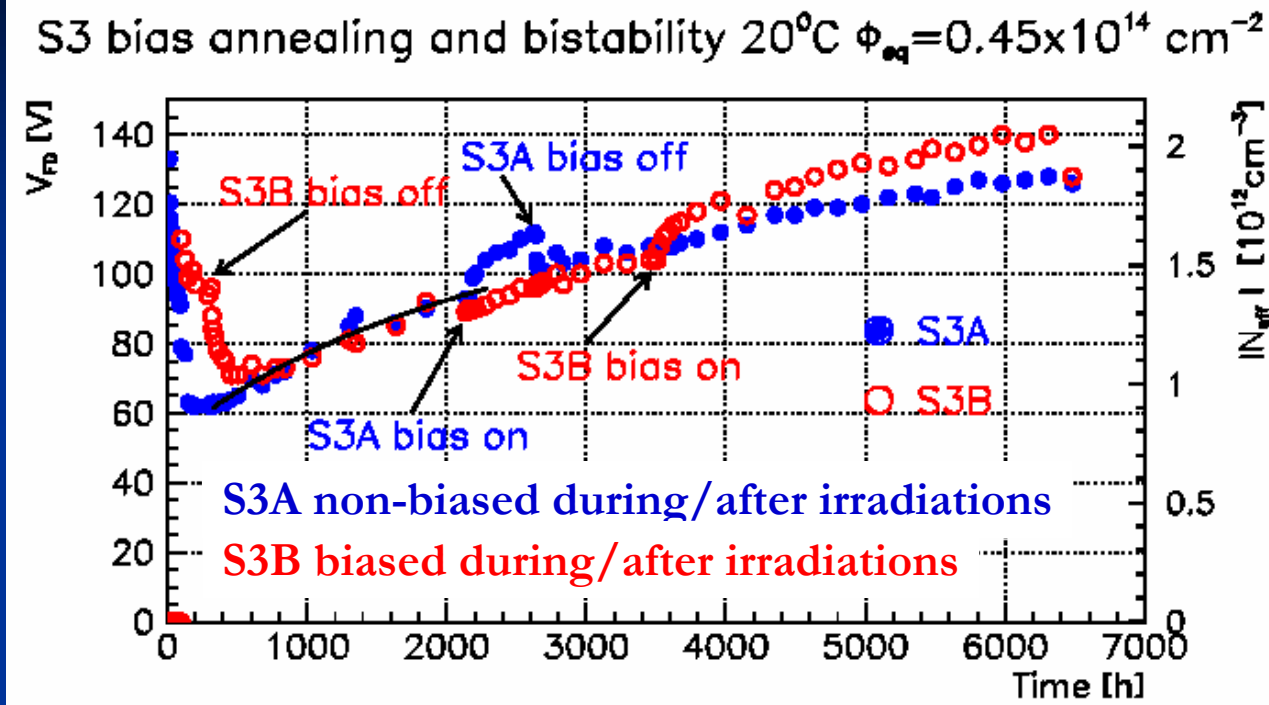
G. Kramberger, V. Cindro, I. Mandić, D. Šuligoj, M. Mikuž



# Outline

- Reminder of the “bias effect” – RD48 results
  - Observations with the CV
  - Observations with the TCT
- CV measurements with Fz (ST,C-en.), MCz n, Cz-n and Epi-Si irradiated with 24 GeV protons and reactor neutrons
- Leakage current
- Conclusions

# Reminder (I)



**No effect on reverse current!**

## • Bias dependent damage

- $g_c$  bias  $\sim 2 \cdot g_c$  unbiased
- $g_y$  bias  $\sim g_y$  unbiased
- $\tau_{ra}$  bias  $\sim 2 \cdot \tau_{ra}$  unbiased

## • Bistability

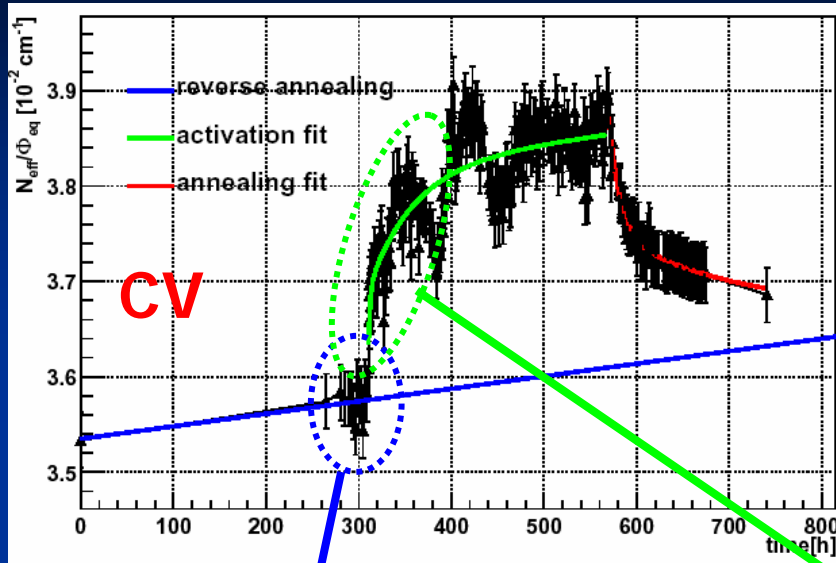
- $g_a \sim 0.4 \cdot 10^{-2} \text{ cm}^{-2}$
- $\tau_a \sim 1 \text{ day @ room temperature, } \sim 100 \text{ d at } -7^\circ\text{C}$
- $\tau_{da} \sim 1 \text{ day @ room temperature}$

First observation: V. Cindro et al, NIM A419 (1998) 132.

Detailed studies: V. Cindro et al, NIM A450 (2000) 288.

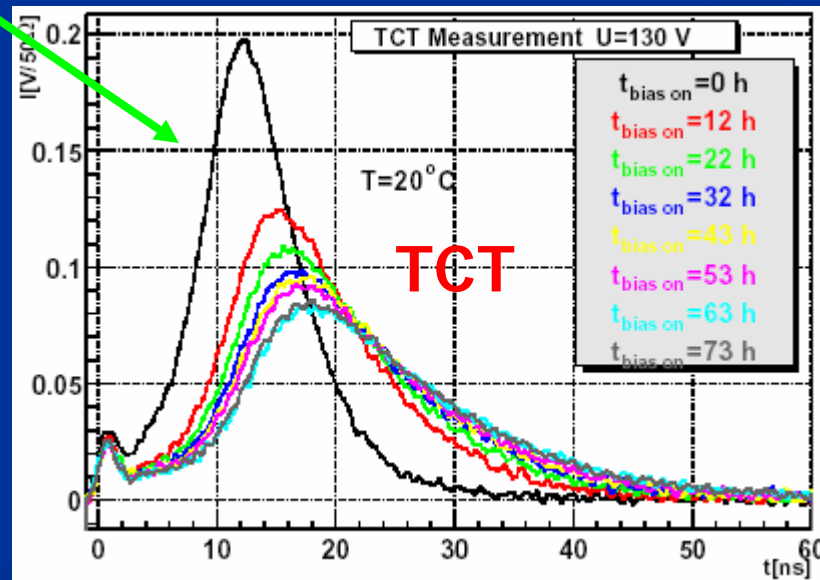
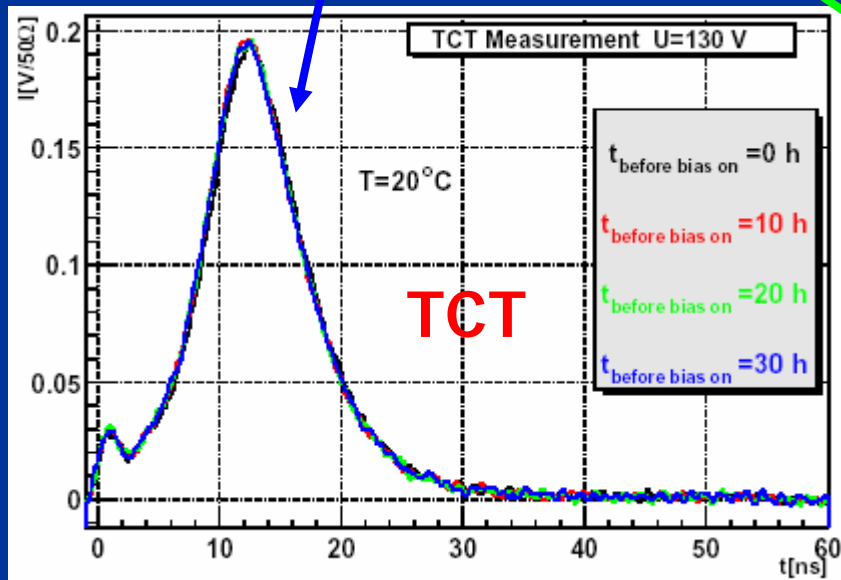
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# Reminder (II)



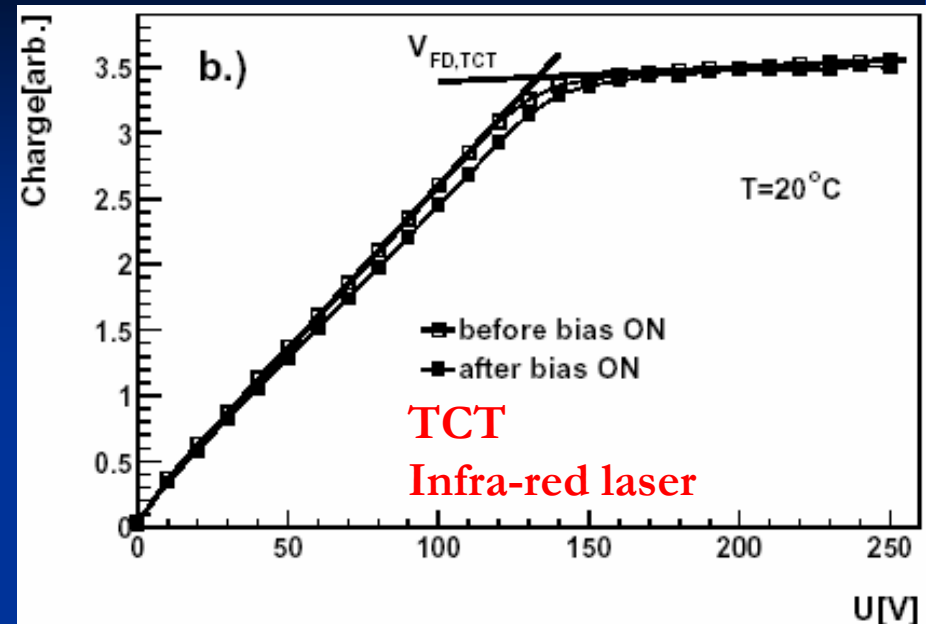
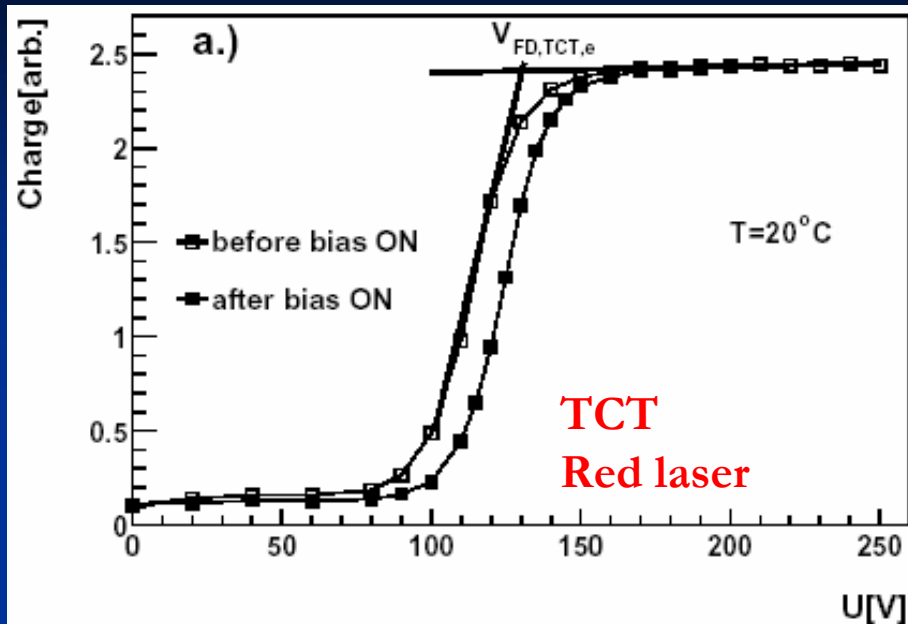
ITE - 5 k $\Omega$ cm (STFZ-n material)  
 Irradiated to  $\Phi_{\text{eq}} = 5 \times 10^{13} \text{ cm}^{-2}$   
 Annealed  $\sim 30\%$  of the reverse annealing  
 $V_{\text{fd}} \sim 130 \text{ V}$

Electron injection **TCT**  
 clear changes in electric field observed!



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# Reminder (III)



$V_{fd}$  from TCT with red laser – electron injection

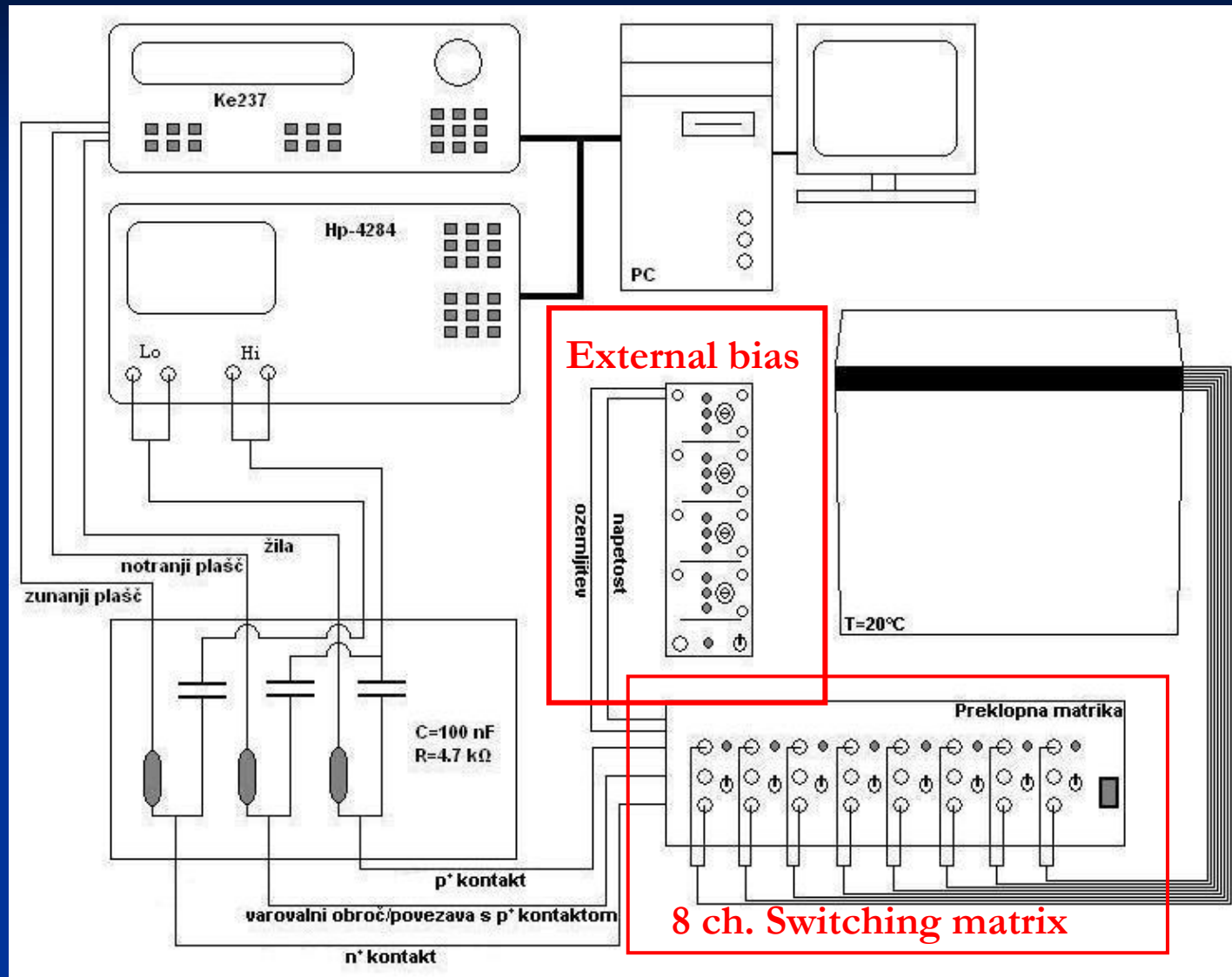
TCT with infrared laser – m.i.p. simulation

A clear increase of  $V_{fd}$  is observed after 70 h of bias applied  
Same amplitudes when measured by TCT or CV!

# What is new 8 years after

- We have materials that don't undergo SCSI (stay n type after irradiation) – according to our previous assumption  $V_{fd}$  should decrease!
- We have material with higher
  - [O] (MCz, Cz, Epi)
  - [C] ( $1.8e16 \text{ cm}^{-3}$ )
  - initial resistivity (as low as  $50 \text{ } \Omega\text{cm}$  for Epi-Si)
- We had measurements with samples irradiated to 24 GeV protons (before 200 MeV pions, neutrons)

# Setup

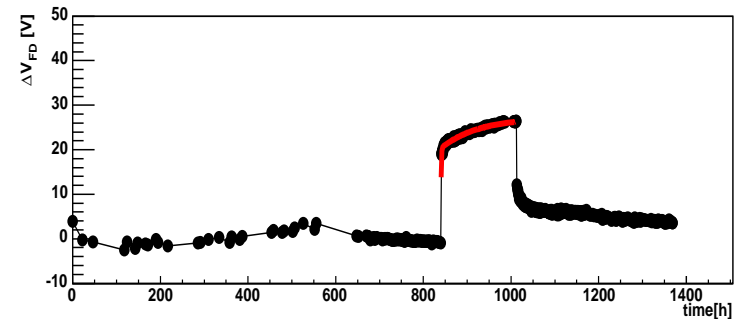
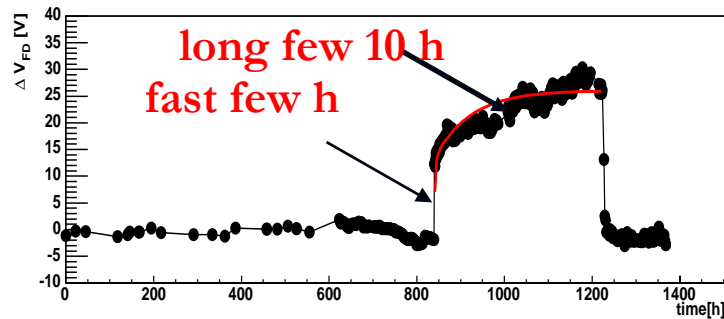
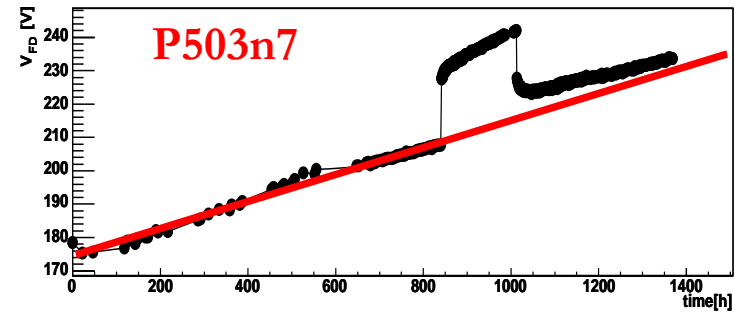
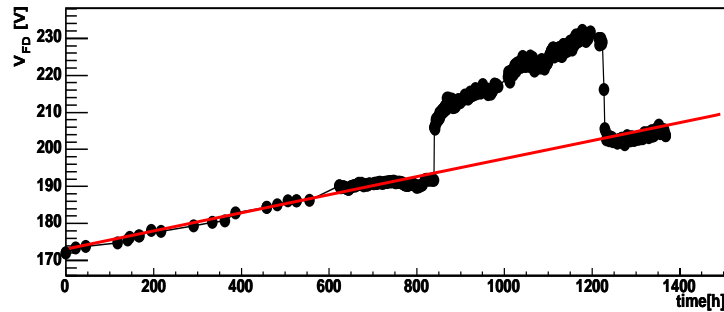


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# STFZ and C-enriched n-irradiated

STFZ-n type (15 kΩcm)  
W339,  $\Phi_{eq} = 10^{14} \text{ cm}^{-2}$

P503n7,  $\Phi_{eq} = 10^{14} \text{ cm}^{-2}$   
[C] =  $1.8 \times 10^{16} \text{ cm}^{-3}$  (SIMS)



$$g_b \sim 3.6 \times 10^{-3} \text{ cm}^{-1}$$

$$g_b \sim 3.7 \times 10^{-3} \text{ cm}^{-1}$$

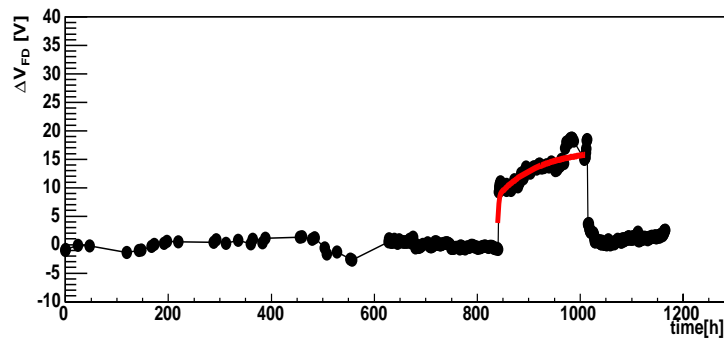
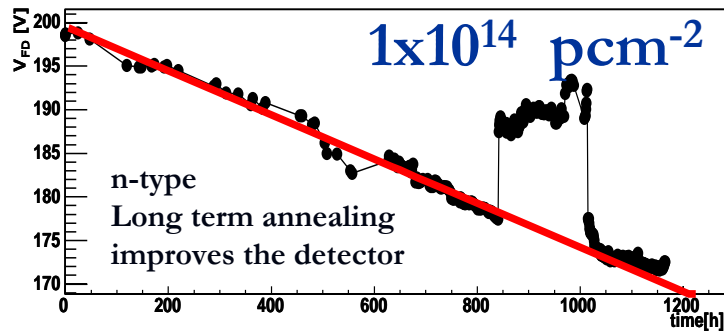
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# MCz-n , 24 GeV protons

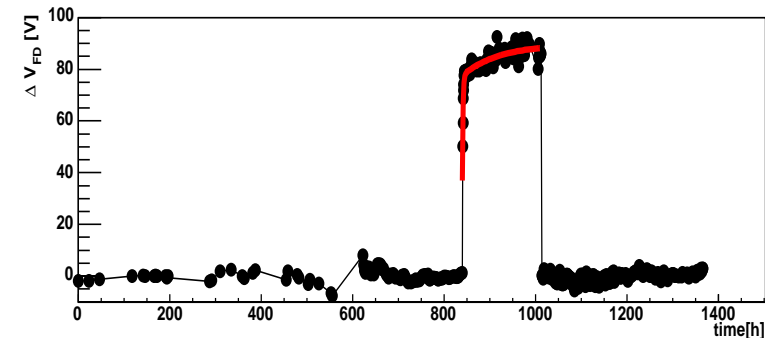
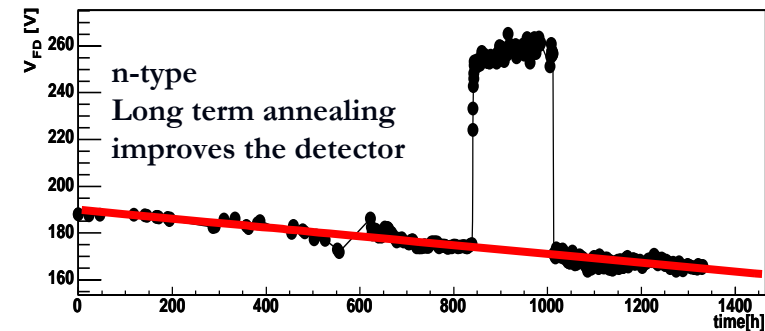
MCz-n type (15 kΩcm)

$$\Phi_{eq} = 0.62 \cdot 10^{14} \text{ cm}^{-2}$$



MCz-n type (15 kΩcm)

$$\Phi_{eq} = 3.1 \cdot 10^{14} \text{ cm}^{-2}$$



$$g_b \sim 3.5 \cdot 10^{-3} \text{ cm}^{-1}$$

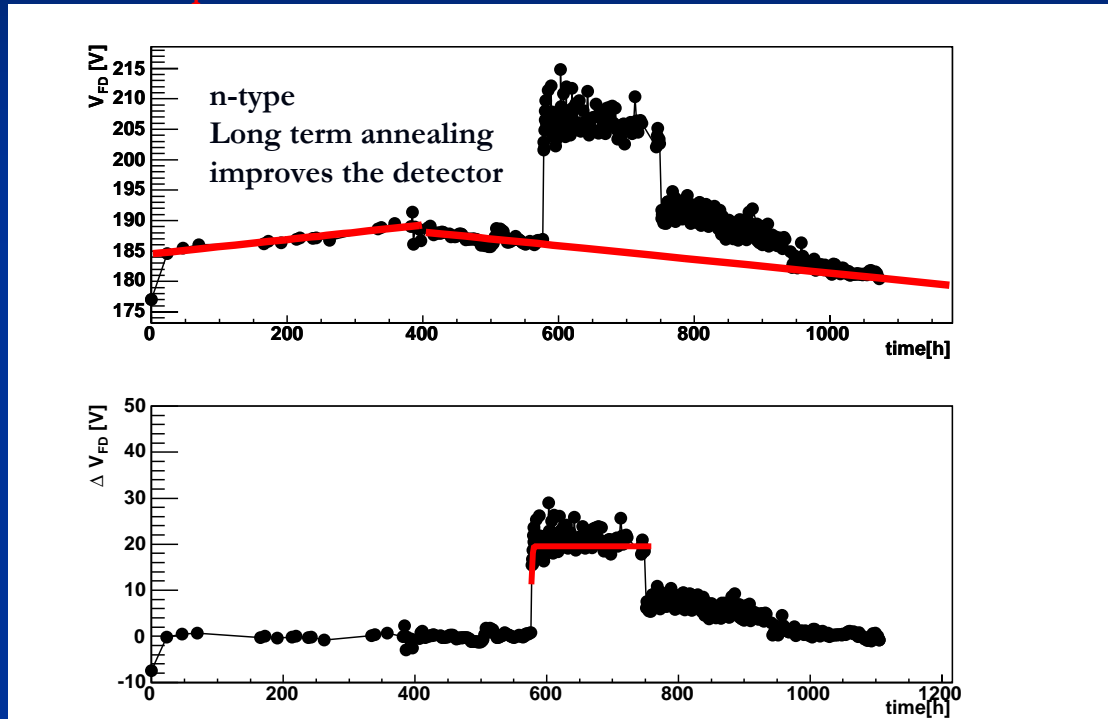
$$g_b \sim 4.2 \cdot 10^{-3} \text{ cm}^{-1}$$

Increase of  $V_{fd}$  also for n-type material -> What would be the explanation?  
Does it has something to do with leakage current-polarization?

# Cz-n , 24 GeV proton

Cz-n type (15 kΩcm) - Sumitomo

$$\Phi_{eq} = 0.75 \cdot 10^{14} \text{ cm}^{-2}$$

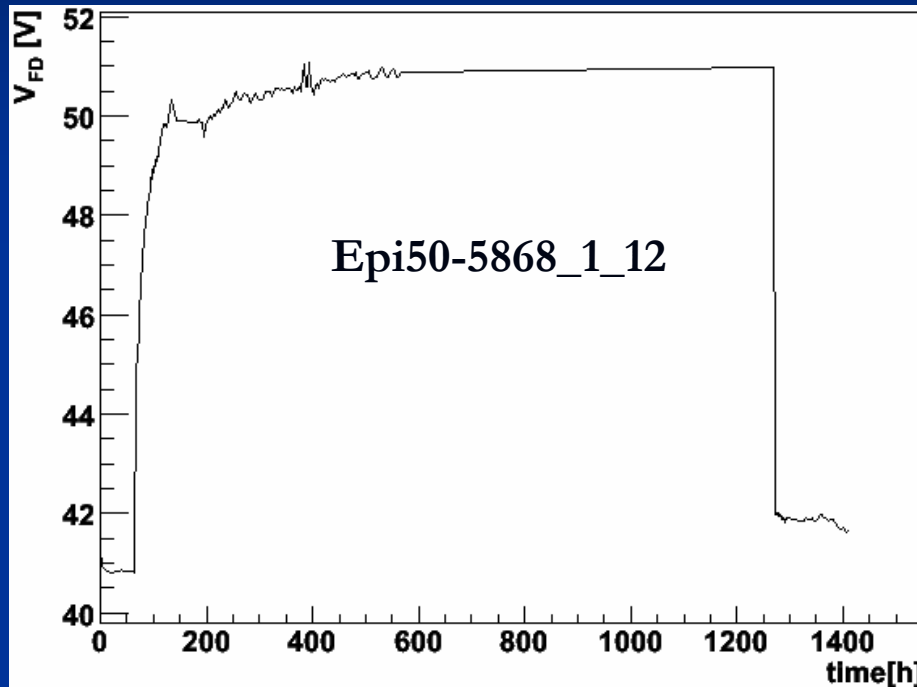


$$g_b \sim 3.9 \cdot 10^{-3} \text{ cm}^{-1}$$

$\tau_a \sim \text{few h}$  at room temperature (very fast increase)

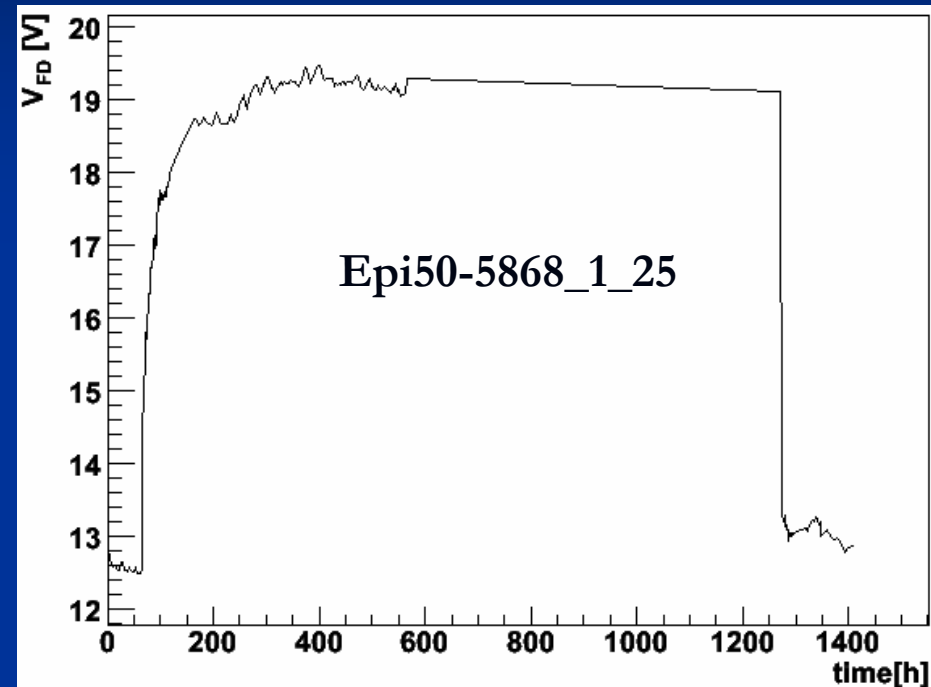
# Epi-Si 50 $\mu\text{m}$ , neutrons

Epi-n type (50  $\Omega\text{cm}$ ) ITME  
 $\Phi_{\text{eq}} = 0.75 \cdot 10^{14} \text{ cm}^{-2}$



$$g_b \sim 2.9 \cdot 10^{-3} \text{ cm}^{-1}$$

Epi-n type (50  $\Omega\text{cm}$ ) ITME  
 $\Phi_{\text{eq}} = 0.75 \cdot 10^{14} \text{ cm}^{-2}$



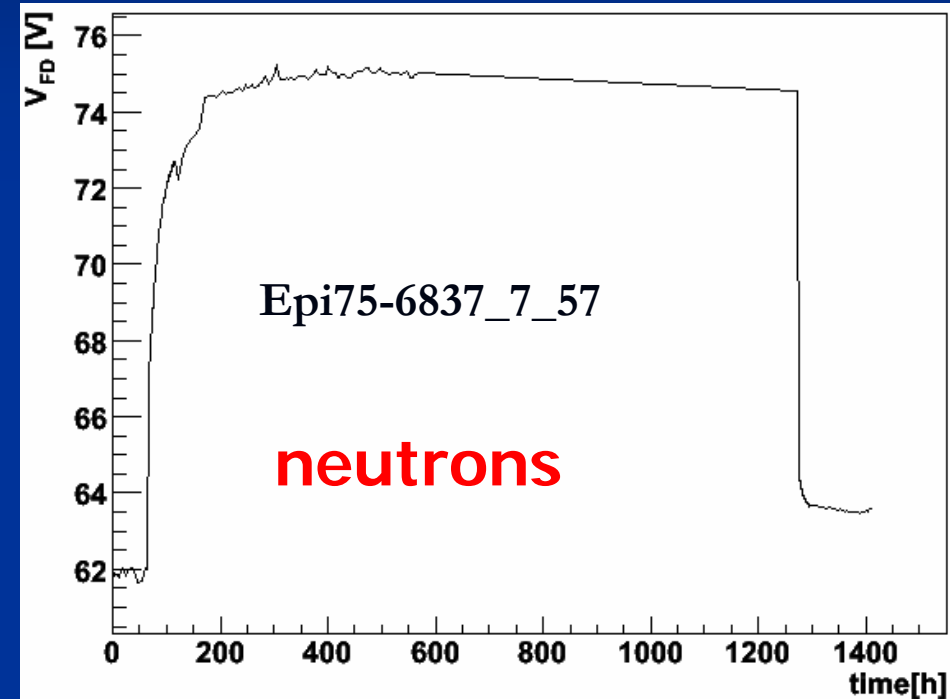
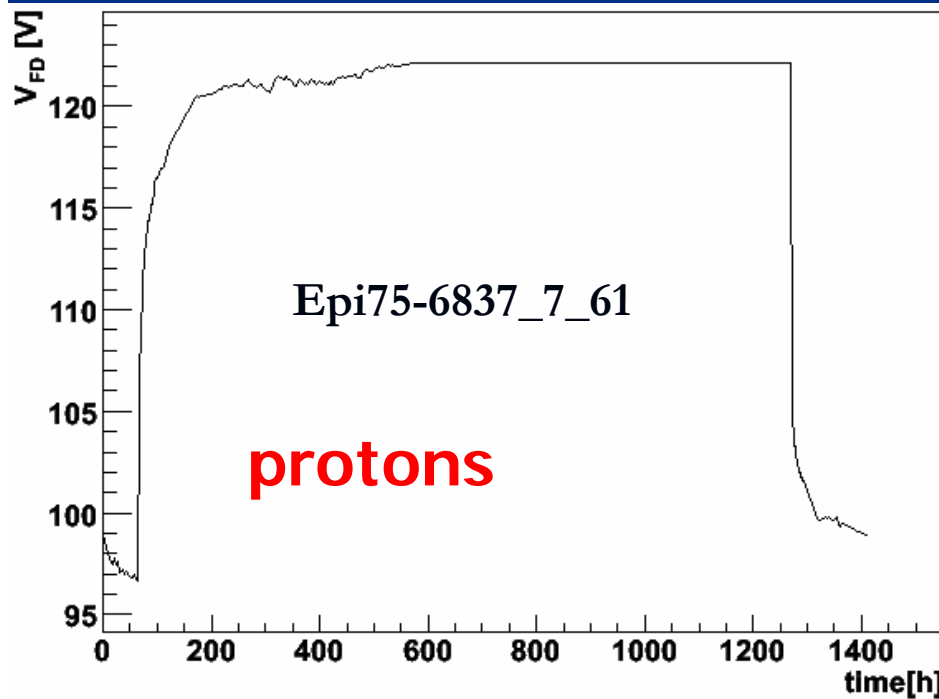
$$g_b \sim 3.4 \cdot 10^{-3} \text{ cm}^{-1}$$

# Epi-Si 75 $\mu\text{m}$

Annealed for 20000 h at 20°C

Epi-n type (50  $\Omega\text{cm}$ ) ITME  
 $\Phi_{\text{eq}} = 1.3 \cdot 10^{15} \text{ cm}^{-2}$  (protons)

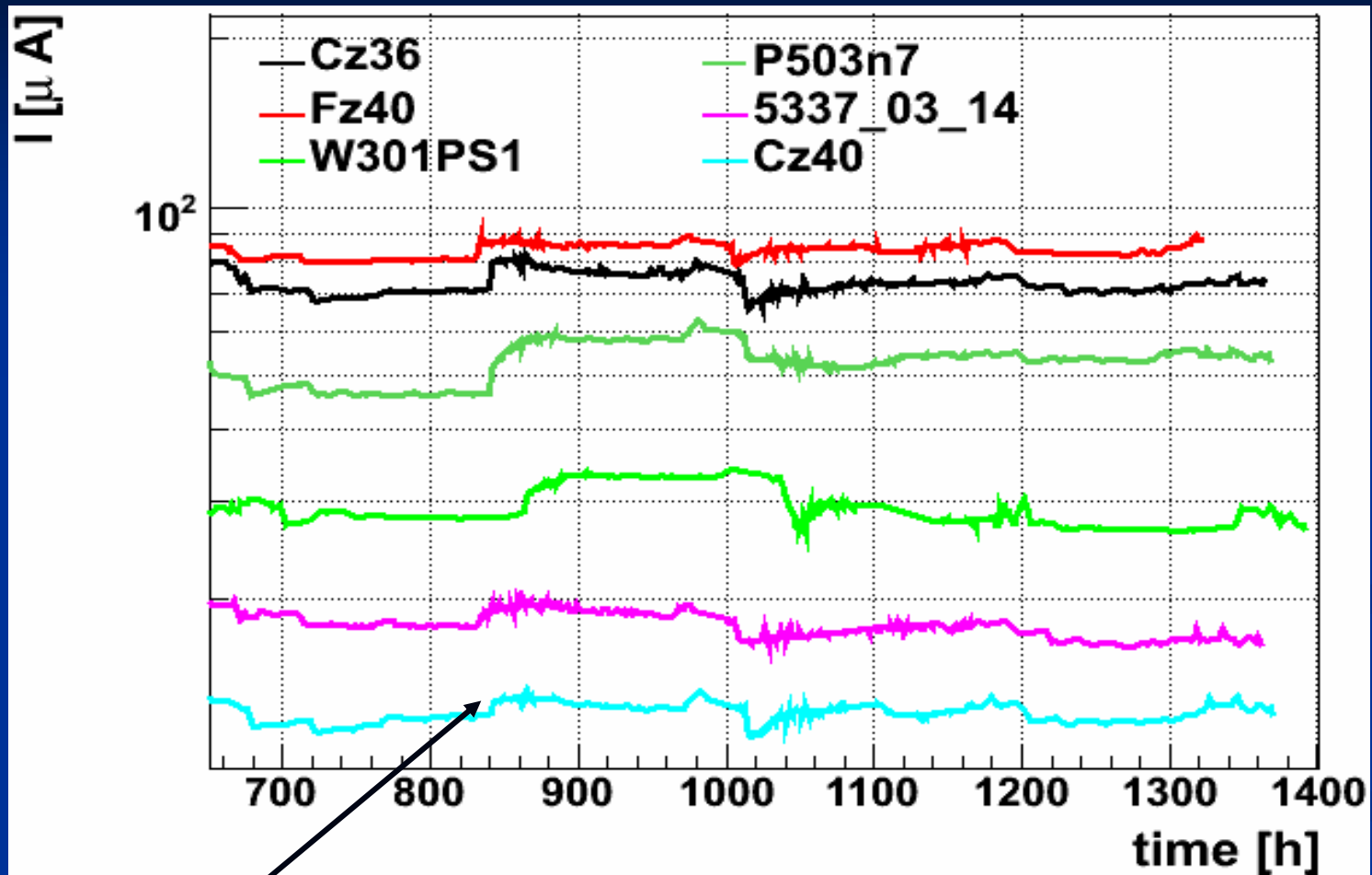
Epi-n type (50  $\Omega\text{cm}$ ) ITME  
 $\Phi_{\text{eq}} = 1 \cdot 10^{15} \text{ cm}^{-2}$  (neutrons)



$$g_b \sim 4.3 \cdot 10^{-3} \text{ cm}^{-1}$$

$$g_b \sim 3.1 \cdot 10^{-3} \text{ cm}^{-1}$$

# Leakage current



Not-ideal IV characteristic (increase of current with voltage also after  $V_{fd}$ )

**No effect on leakage current increase!**

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# Conclusion

- Bistability is there also for Epi, Cz, MCz materials at the approximately the same introduction rate ( $0.4 \cdot 10^{-2} \text{ cm}^{-1}$ ) and activation and decay time constants (fast few h and slow few 10 h at room temperature)
- It is also present for 24 GeV irradiated samples (expected)!
- What is the cause we don't know!
- Is it important? Yes!
  - we need to accommodate operation scenario.
  - we need to extract activation energy to be able to scale the effect to more realistic ( $-10^\circ\text{C}$ ) temperatures
- Future work: Is it present also in p-type material?